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Estimating technical efficiency in micro panels

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A B S T R A C T

Bootstrap confidence intervals on fixed-effects efficiency estimates in micro panels exhibit low coverage probabilities. We propose an alternative efficiency measure involving the mean of the firm effects. With the same estimated efficiency ranks as the traditional measure, its corresponding bootstrap confidence intervals have better coverage probabilities.

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1. Introduction

In the panel stochastic frontier literature, fixed-effects estimation (Schmidt and Sickles, 1984) has the advantage of not requiring distributional assumptions on the error components. Consequently, the model is often employed in empirical research (e.g., Kumbhakar, 1987 and Bauer and Hancock, 1993). Confidence intervals for technical efficiency may be based on asymptotic normality, when the sample size is large (Horrace and Schmidt, 1996). However, in micro panels with small time dimensions, the preferred method of constructing confidence intervals without distributional assumptions is to perform the bootstrap. Simar (1992), Simar and Wilson (1998), Hall et al. (1993), and Kim et al. (2007) investigate confidence interval coverage rates for various bootstrap techniques based on the fixed-effects estimation, and find that the coverage is generally poor when the time dimension of the data is small. As discussed in Kim et al. (2007), the coverage erosion is due to the bias induced by the estimated maximum of the firm effects involved in the traditional efficiency estimate (Schmidt and Sickles, 1984). The received literature encourages techniques that improve coverage rates by accounting for this bias. However, the improved coverage of bootstrap confidence intervals is still not satisfactory in micro panels with small time dimensions and large numbers of firms. Even worse, when “ties” among firms occur (i.e., several firms are equally best) no bootstrap confidence intervals are reliable (Kim et al., 2007). Recently, Satchchai and Schmidt (2010) show that removing the “max” operator bias is possible using the generalized panel jackknife, but the resulting estimate has a large variance.

We approach this inference problem from a different perspective. The traditional efficiency measure defined in Schmidt and Sickles (1984) shifts the firm-specific effects by their maximum. We propose an alternative measure which shifts the firm effects by their mean. This efficiency measure yields the same efficiency rank of firms as the traditional measure. However, unlike the estimated maximum of firm effects, the estimated mean is unbiased, so the corresponding bootstrap confidence intervals for the new measures have better coverage probabilities. Thus, when the inference based on the traditional efficiency measure is inaccurate in micro panels or in the case that the identity of the best firm is uncertain, the proposed measure can be used as an alternative and reliable way to estimate firms’ technical efficiencies. It should be made clear at the outset that the proposed measure is not a substitute for the traditional measure; it is an additional metric that should be a part of the empiricist’s toolbox.

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2. Fixed-effects efficiency measures

In a stochastic frontier model for panel data,

\[ y_{it} = \alpha + \xi_{it} \beta - u_i + v_{it}, \quad i = 1, \ldots, N, \quad t = 1, \ldots, T. \]  \hfill (1)

The technical inefficiency of firm \( i \) is characterized by the time-
invariant \( u_i \geq 0 \). The idiosyncratic disturbance \( v_{it} \) is assumed
i.i.d. \((0, \sigma^2)\). Usually, technical efficiency is defined as \( r_i = \exp(-u_i) \) under a logarithmic specification of the Cobb–Douglas
production function. The slope parameter \( \beta \) can be estimated
consistently using fixed-effects estimation. Call this estimate \( \hat{\beta} \). The
firm-specific production level (or firm effect) \( \alpha_i = \alpha - u_i \) can be estimated by \( \hat{\alpha}_i = \bar{y}_i - \bar{x}_i \hat{\beta} \), where \( \bar{y}_i \) and \( \bar{x}_i \) are within-
group averages. Since \( u_i \) cannot be identified without additional
assumptions, Schmidt and Sickles (1984) suggest the relative
expected efficiency measure,

\[ u_i^* = u_i - \min_j u_j = \max_j \alpha_j - \alpha_i, \quad r_i^* = \exp(-u_i^*), \]

with fixed-effects estimates,

\[ \hat{\alpha} = \max_j \hat{\alpha}_j, \quad \hat{\alpha}_i^* = \hat{\alpha} - \hat{\alpha}_i, \quad \hat{r}_i^* = \exp(-\hat{u}_i^*). \]

Per Schmidt and Sickles (1984), \( \hat{\beta} \) converges to \( \beta \) for large \( N \) or
\( T \), while \( \hat{\alpha}_i \) converges to \( \alpha_i \) for large \( T \) only. Therefore, in micro
panels with small \( T \), asymptotic approximations for confidence
intervals on functions of \( \alpha_i \) are inappropriate, and a bootstrap
method should be employed.

Kim et al. (2007) provide a detailed discussion of methods
for bootstrap confidence intervals for technical efficiency \( r_i^* = \exp(\alpha_i - \max_j \alpha_j) \), including percentile intervals, bias-corrected
with acceleration (BCa) intervals, bias-corrected (BC) percentile
intervals and a parametric method. Overall, BCa and BC percentile
seem preferred considering the coverage and width of the intervals.
However, in their simulation study (Kim et al., 2007, Table 3),
even the BCa intervals and BC percentile intervals have low coverage
rates in the usual panel case. For example, the coverage rate of the
BCa intervals with nominal 90% significance is only 68.7% when
\( N = 100, \quad T = 10, \quad \gamma = 0.1 \).\footnote{The relationship between inefficiency and unobserved heterogeneity is not
considered here. For a detailed discussion of this issue, see Greene (2004, 2005).}
The corresponding BC percentile intervals have slightly higher coverage than BCa intervals, but with bigger width. As we will see, the coverage rate is even lower when
\( T < 10 \) and \( N > 100 \). The problem arises from the “max” operators in \( \hat{\alpha}_i^* \) and \( \hat{r}_i^* \). Per Kim et al. (2007), the “max” operator induces an
upward bias in \( \hat{\alpha} \) and \( \hat{r} \), and hence a downward bias in \( \hat{\alpha}_i \).
The “max” operator favors positive noise. When \( T \) is large, \( \hat{\alpha}_j \rightarrow \alpha_j, \max_j \hat{\alpha}_j \rightarrow \max_j \alpha_j, \) and the “max” operator bias is mitigated.
However, this bias cannot be ignored in micro panels with small \( T \)
and large \( N \), which is the focus of this paper.

Since the “max” operator bias is the main source of the inaccurate inference for technical efficiency in micro panels, removing the bias could be a solution. A successful attempt of
bias correction is made by Satchachai and Schmidt (2010) using the
generalized panel jackknife, but the resulting estimate has
a large variance. Alternatively, Feng and Horrace (2012) propose two
efficiency measures involving \( \min_j \alpha_j \), whose corresponding
fixed-effects estimates preserve the same ranking as \( \hat{r}_i^* \). Although
the bias issue persists for the fixed-effects estimates of their two
measures, they show that bias is mitigated in certain situations
related to the skew of the efficiency distribution.

This paper approaches this inference problem from a different
perspective. Since the sample ranking of estimators \( \hat{r}_i^* = \exp(\hat{\alpha}_i - \max_j \hat{\alpha}_j) \) is the same as the ranking of unbiased estimators \( \hat{\alpha}_i \)
with \( \hat{r}_i^* = \exp(\hat{\alpha}_i - \hat{\alpha}_i) \), it seems possible to construct an
alternative efficiency measure containing the same information
as \( r_i^* \) but without the “max” operator bias and its related issues.
The traditional measure \( r_i^* \) is a monotonically increasing transformation of \( \alpha_i - \max_j \alpha_j \), a shift of \( \alpha_i \) by \( \max_j \alpha_j \). Using the maximum can be regarded as a normalization to produce efficiency 1 for the firm
with the largest \( \alpha_i \) in the sample. Similar in spirit to \( r_i^* \), we propose
an efficiency measure,

\[ E_i = h \left( \alpha_i - \frac{1}{N} \sum_j \alpha_j \right), \]

where \( h \) is a monotonically increasing transformation. \( E_i \) has the
same efficiency rank of firms as \( r_i^* \) in the sample. Unlike \( r_i^* \), our
measure \( E_i \) shifts \( \alpha_i \) by the mean \( \frac{1}{N} \sum_j \alpha_j \). \( E_i = h(\hat{\alpha}_i - \frac{1}{N} \sum_j \hat{\alpha}_j) \) is the estimate of \( E_i \).

In general, \( E_i \) can be arbitrarily restricted to \((0, 1)\), so that
efficiency can be expressed as a percentage.\footnote{The usual measure of technical efficiency, \( r_i = \exp(-u_i) \), implies that the
production function is Cobb–Douglas. However, if the true data-generating process
is not Cobb–Douglas, then \( r_i = \exp(-u_i) \) is not technical efficiency, per se, but
merely an indicator of technical efficiency. The proposed measure is simply another
such indicator.} There are an
unlimited number of functions one might use. For example, we consider the function form of standard normal cumulative distribution function \( \Phi \),

\[ E_i = \Phi \left( \alpha_i - \frac{1}{N} \sum_j \alpha_j \right), \]

with estimate

\[ \hat{E}_i = \Phi \left( \hat{\alpha}_i - \frac{1}{N} \sum_j \hat{\alpha}_j \right). \]

The advantage of using a symmetric and smooth cumulative
distribution function is that \( E_i = 0.5 \) is a meaningful reference
point corresponding to a firm with the mean value of \( \alpha_i \). Alternative distributions (e.g., Cauchy, student, logistic) can be used for this
purpose.

As discussed above, the estimated maximum, \( \max_j \hat{\alpha}_j \), is biased.
This is the main source of the coverage erosion of \( r_i^* \)’s bootstrap
confidence intervals. By contrast, the estimated mean \( \frac{1}{N} \sum_j \alpha_j \)
is unbiased as the estimated firm effects \( \hat{\alpha}_i \) are unbiased. Since
\( \hat{\alpha}_i - \frac{1}{N} \sum_j \hat{\alpha}_j \) unbiased, the percentile bootstrap confidence
intervals for \( \alpha_i - \frac{1}{N} \sum_j \alpha_j \) have no coverage erosion and thus
have high coverage even in micro panels. According to Efron and
Tibshirani (1993), the percentile bootstrap confidence intervals are
transformation respecting, implying that the percentile intervals for
\( E_i \) will have the same coverage rate as those for \( \alpha_i - \frac{1}{N} \sum_j \alpha_j \).
Therefore, we can always construct percentile intervals for \( E_i \)
by transforming the intervals for \( \alpha_i - \frac{1}{N} \sum_j \alpha_j \). Hence, simple
bootstrap confidence intervals like the percentile bootstrap are
enough for accurate inference. For empiricists, inference on \( E_i \)
will be considerably easier to implement than inference on \( r_i^* \).
Moreover, the bootstrap confidence intervals for \( E_i \) are more
reliable than those for the traditional measure \( r_i^* \), no matter how
many firms there are, and whether or not the identity of the best
firm is in serious doubt.

\[ E_i = 0.5 \text{ for the firm with mean value of } \alpha_i \text{ in (2), so we call}
\]
\[ \text{the firm with } E_i = 0.5 \text{ the } mean \text{ firm}. \]

The efficiencies of all firms
3. Simulations and empirical example

To better understand the accuracy of inference for the traditional measure \( r^* = \exp(\alpha_i - \max(\alpha_j)) \) and our proposed measure \( \tilde{E}_i = \Phi(\alpha_i - 1/n \sum \alpha_j) \), we conduct Monte Carlo experiments to compare the coverage rate of bootstrap confidence intervals in micro panels. The data-generating process used here follows the procedure in Kim et al. (2007): \( y_{it} = \gamma - u_t + v_{it} \), with \( v_{it} \sim i.i.d.N(0, \sigma^2) \) and \( u_t \sim i.i.d.N(0, \sigma_u^2) \). We set \( \alpha = 1 \) and define \( \gamma = \text{Var}(u)/(\sigma^2 + \text{Var}(u)) \). Small \( \gamma \) indicates a particularly noisy experiment. A large \( \gamma \) (close to 1) means there is little variation in the idiosyncratic error \( v_{it} \). The Monte Carlo parameters are \( (\gamma, N, T) \). When \( T \) is large, the bias issue of traditional efficiency estimate is mitigated. Here, we consider the interesting case when the inference of the traditional measure \( r^* \) is inaccurate in micro panels with \( T = 4, 6, 10 \). Experiments are conducted with \( N = 20, 50, 100 \) and 150, and \( \gamma = 0, 0.1, 0.3 \) and 0.5, with 1000 bootstrap replications. We repeat the Monte Carlo experiments 1000 times.

Kim et al. (2007) show that the BC\( a \) bootstrap confidence intervals and BC percentile intervals for \( r^* \) are better than other intervals, so we report these two intervals. The percentile intervals are also presented for comparison. Since \( \hat{\alpha}_i - 1/n \sum \hat{\alpha}_j \) is unbiased, only percentile intervals for \( \tilde{E}_i \) are presented. Simulated 90% nominal coverage rates for intervals for \( r^* \) and \( \tilde{E}_i \) are in Table 1. The coverage of percentile intervals for \( r^* \) are much better than those in Table 1, and therefore, unreliable for panels with small \( T \) and large \( N \). For example, the coverage of the 90% nominal percentile interval (column 4) is 24.6% for \( T = 6, N = 150 \) and \( \gamma = 0.5 \). As expected, the coverage rates for both BC\( a \) (column 6) and the bias-correct percentile (column 8) intervals improve, but are still far from satisfactory. The coverage rates of BC\( a \) and the BC percentile intervals for \( r^* \) are 41.0% and 68.5% respectively for \( T = 6, N = 150 \) and \( \gamma = 0.5 \). Since \( \hat{\alpha}_i - 1/n \sum \hat{\alpha}_j \) is unbiased, the percentile bootstrap confidence intervals for \( \alpha_i = 1/n \sum \alpha_j \) have no coverage erosion. Since \( E_i \) is a monotonic function of \( \alpha_i - 1/n \sum \alpha_j \), its percentile bootstrap confidence intervals have the same coverage as those for \( \alpha_i = 1/n \sum \alpha_j \). Unlike the bootstrap confidence intervals for \( r^* \), the coverage rates of percentile intervals for \( E_i \) (column 9) are effectively constant across \( N \) and \( \gamma \). They are only related to \( T \). The coverage rates of percentile intervals for \( E_i \) are about 75%, 81% and 85% for \( T = 4, 6, 10 \), respectively. Therefore, based on coverage rates, the confidence intervals for \( E_i \) are much more informative and robust than those for \( r^* \).

Table 2 contains the point estimates and bootstrap intervals for \( r^* \) and \( \tilde{E}_i \). We report results for the best farm, the 99th, 75th, median, 25th, 1th quantile, and the worst farm in rank order. The first column is the farm number. The third column contains the estimates of the firm effects \( \alpha_i = \gamma - u_i \). The second interesting to note that the point estimator \( \tilde{E}_i \) (column 5) is similar in magnitude to \( r^* \) (column 4) at the bottom end of the order statistic. Compare 0.336–0.366 for farm 45 and 0.349–0.379 for farm 117. If one is interested in inference on the least efficient farms in the sample, then \( \tilde{E}_i \) gives point estimates similar to \( r^* \) but with higher coverage rates (but for different measures). Fig. 1 contains the graphs of \( \tilde{r}_i \).
Simulated evidence suggests that, in micro panels with small $T$ and large $N$, development of new efficiency measures may be as important as developing improved bootstrap interval techniques for the traditional measure $r^*$ to ensure reliable inference on efficiency. We have investigated one rank-preserving efficiency measure and its fixed-effects estimate that avoids the “max” operator, whose bootstrap intervals are transformation respecting, and that produces good coverage rates. Unlike the traditional measure $r^*$, the new measure, $E_*$, uses a reference point based on the mean, which can be unbiasedly estimated. Consequently, the new efficiency estimate $E_*$ has no bias issue as does $r^*$. Monte Carlo simulations show that the simple percentile bootstrap confidence intervals for $E_*$ exhibit high coverage rates in micro panels. We might conclude that the new efficiency measure $E_*$ (and similar measures) are the only way to ensure accurate inference in micro panels. However, empiricists face a trade-off between the statistical accuracy of inference and the empirical relevance of the estimated measure. It may be the case that $E_*$ is not a reasonable substitute for $r^*$ in any particular empirical exercise. As such, $E_*$ should be regarded as a complement to $r^*$ and a potentially important addition to the empiricist’s toolbox.

4. Conclusions

Simulated evidence suggests that, in micro panels with small $T$ and large $N$, development of new efficiency measures may be as important as developing improved bootstrap interval techniques for the traditional measure $r^*$ to ensure reliable inference on efficiency. We have investigated one rank-preserving efficiency measure and its fixed-effects estimate that avoids the “max” operator, whose bootstrap intervals are transformation respecting, and that produces good coverage rates. Unlike the traditional measure $r^*$, the new measure, $E_*$, uses a reference point based on the mean, which can be unbiasedly estimated. Consequently, the new efficiency estimate $E_*$ has no bias issue as does $r^*$. Monte Carlo simulations show that the simple percentile bootstrap confidence intervals for $E_*$ exhibit high coverage rates in micro panels. We might conclude that the new efficiency measure $E_*$ (and similar measures) are the only way to ensure accurate inference in micro panels. However, empiricists face a trade-off between the statistical accuracy of inference and the empirical relevance of the estimated measure. It may be the case that $E_*$ is not a reasonable substitute for $r^*$ in any particular empirical exercise. As such, $E_*$ should be regarded as a complement to $r^*$ and a potentially important addition to the empiricist’s toolbox.

References


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If we construct an efficiency measure without normalization at the mean, e.g., $\Phi(\alpha_i)$, the estimated efficiencies of firms could fall either around 0 or 1. This depends on the magnitude of estimated $\alpha_i$ in a sample. For example, using this empirical sample, all estimated efficiencies based on measure $\Phi(\alpha_i)$ are nearly 1. In this case, without normalization it seems inconvenient to use these efficiencies directly in practice.